
ACCELERATOR-BASED STRUCTURAL INVESTIGATION OF SEMICONDUCTOR NANOCRYSTALS

Furkan Isik^{1,*}, Betul Canimkurbey²,

¹*Institute of Accelerator Technologies, Ankara University; Turkish Accelerator and Radiation Laboratory (TARLA), Ankara 06830, Turkiye*

²*Department of Physics, Polatli Faculty of Arts and Sciences, Ankara Hacı Bayram Veli University, Ankara 06900, Turkiye*

ABSTRACT

This study employs synchrotron-based X-ray absorption spectroscopy (XAFS) to resolve the local elemental arrangements and interfacial bonding within complex colloidal semiconductor heterostructures. By performing multi-edge measurements, we systematically map the atomic distribution across internal boundaries as structural complexity increases. Through coordinated analysis of X-ray absorption near edge structure (XANES) and extended X-ray absorption fine structure (EXAFS) data, we determine critical structural parameters, including interatomic distances (R), coordination numbers (N) and Debye-Waller factors (σ^2). Our results provide evidence of a material gradient at the internal interfaces, revealing that the prevailing interatomic bonds are highly sensitive to the size of the initial core. Furthermore, we address the temporal stability of these systems under ambient conditions. Long-term spectroscopic monitoring over long periods of time indicates that while the internal core remains structurally robust, surface-related bonds undergo partial degradation and atomic reorganization. This research represents a comprehensive experimental assessment of the local atomic order in incrementally heterogeneous quantum-confined systems. The findings offer fundamental insights into how precise elemental arrangements at the nanoscale dictate the electronic and emissive properties of advanced semiconductor materials.

Keywords Synchrotron · XAFS · Colloidal semiconductors

*Corresponding Author's E-mail: fisik@ankara.edu.tr